## **Supporting Information**

## Thickness Optimization of Highly Porous Flame-Aerosol Deposited WO<sub>3</sub> Films for NO<sub>2</sub> Sensing at ppb

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**Table S1.** Optimum WO<sub>3</sub> temperatures for NO<sub>2</sub> sensing. Reported optimum operating temperatures for undoped WO<sub>3</sub> films prepared by wet-phase deposition and sputtering. WO<sub>3</sub> - based sensors are most sensitive to NO<sub>2</sub> at low temperatures, with observed optima typically below 150 °C, while higher optima were mainly reported for sputtered, thus, dense films. Abbreviations: n/a: not available.

Material	Film fabrication method	Film thickness [µm]	Optimum Temperature [ $^{\circ}$ C]	Ref.	
WO <sub>3</sub> hollow microspheres	Coating	n/a	75	[22]	
WO3 yolk-shell spheres	Drop-coating	~12	<100	[21]	
WO <sub>3</sub>	Printing of a paste	~30	100	[91]	
WO <sub>3</sub>	Coating	n/a	120	[12]	
WO <sub>3</sub>	Coating	n/a	125	[46]	
WO <sub>3</sub>	Spin-coating	n/a	<150	[92]	
WO <sub>3</sub>	Sputtering	0.085	150	[23]	
WO <sub>3</sub> nanorods	Pressing into discs	~500	200	[93]	
WO <sub>3</sub>	Sputtering	0.360	200	[94]	
WO <sub>3</sub>	Spin-coating	2.3-3.0	250	[95]	
WO <sub>3</sub>	Sputtering	0.2 and 0.05	350	[96]	

**Table S2.** Porosity evaluation by X-ray diffraction. Film porosity of flame-deposited WO<sub>3</sub> films on Al<sub>2</sub>O<sub>3</sub> substrates evaluated at different XRD peak positions of Al<sub>2</sub>O<sub>3</sub>. Larger Al<sub>2</sub>O<sub>3</sub> substrates (20 x 20 mm<sup>2</sup>) were used for the evaluation as the microsensors were too small to be evaluated by XRD.

Deposition time	Porosity evaluated at different Al <sub>2</sub> O <sub>3</sub> peak positions (20) [%]						
[min]	<b>25.6</b> °	<b>35.1</b> °	<b>43.3</b> °	57.5 °	Avg. ±SD		
1	97.1	97.0	96.9	96.6	$96.9 \pm 0.2$		
2	97.7	97.4	97.8	97.7	$97.6 \pm 0.2$		
4	96.9	96.7	96.7	96.8	$96.8 \pm 0.1$		
8	97.1	96.9	97.0	96.8	$96.9 \pm 0.1$		

12	96.9	96.6	96.6	96.5	96.7 ±0.2
18	96.9	96.5	96.6	96.5	96.6 ±0.2

**Table S3.** Film thickness effect on selectivity. NO<sub>2</sub> selectivity comparison over major interferents for different WO<sub>3</sub> film thicknesses. Films were operated at 125  $^{\circ}$ C and 50% RH (at 23  $^{\circ}$ C).

Film thickness	Deposition time	NO2 selectivity (SNO2/Sanalyte) [-]								
[µm]	[min]	$H_2$	NH <sub>3</sub>	CH4	MeOH	EtOH	Acetone	со	H <sub>2</sub> S	FA
0.5	1 min	>10 <sup>5</sup>	>104	>10 <sup>5</sup>	>10 <sup>5</sup>	>10 <sup>5</sup>	$> 10^{4}$	>10 <sup>5</sup>	415	>10 <sup>5</sup>
3.1	4 min	>10 <sup>4</sup>	>10 <sup>5</sup>	>104	>10 <sup>5</sup>	>10 <sup>5</sup>	$>10^{4}$	>10 <sup>5</sup>	835	>10 <sup>3</sup>
12.3	18 min	>10 <sup>3</sup>	>10 <sup>5</sup>	>10 <sup>5</sup>	>10 <sup>5</sup>	795	>10 <sup>5</sup>	>10 <sup>5</sup>	>10 <sup>3</sup>	>10 <sup>3</sup>



**Figure S1.** Sensor chamber. (a) Top and (b) 3D view of the sensing chamber (top part) with the sensing cavity  $(18.1 \times 16.6 \times 18.0 \text{ mm}^3)$  in its center. Recesses accommodate sealings and circuitry for electrical connections to readout and power equipment. The leadless chip carrier containing the microsensors is thereby mounted to a socket soldered onto a printed circuit board [44], that can be attached to the base of the stainless steel sensor chamber (not shown here).



**Figure S2.** Phase determination by X-ray diffraction. Magnification of the XRD pattern of WO<sub>3</sub> between  $2\theta = 22 - 25.5^{\circ}$ . Reference peaks of  $\varepsilon$ - (circles, ICSD 84163),  $\gamma$ - (triangles, 80056) and  $\delta$ -WO<sub>3</sub> (squares, 80053) with corresponding peak positions are indicated.



**Figure S3.** Extended XRD spectrum of the WO<sub>3</sub> powder. Reference peak position for  $\varepsilon$ -(circles, ICSD 84163),  $\gamma$ -WO<sub>3</sub> (triangles, 80056) and cubic NiO (diamonds, 61324) are indicated. Please note that NiO was added as internal standard for sample displacement correction.



**Figure S4.** Film thickness determination. FIB-SEM images for (a) 1, (b) 2, (c) 4, (d) 8, (e) 12 and (f) 18 min flame-deposited films. Please note the different scale bar in (f). The more compact structures at the cutting edge are caused by melting during FIB.



**Figure S5.** Flame-deposited WO<sub>3</sub> films on Al<sub>2</sub>O<sub>3</sub>. SEM images for a) 1, b) 2, c) 4, d) 8, e) 12 and f) 18 minutes direct WO<sub>3</sub> particle deposition by FSP on Al<sub>2</sub>O<sub>3</sub> substrates along with marks for measuring the average film thickness. Please note the different scale bars that are the same for panels (a,b), (c,d) and (e,f).



**Figure S6.** WO<sub>3</sub> film thickness on Al<sub>2</sub>O<sub>3</sub> as a function deposition time. Films deposited on Al<sub>2</sub>O<sub>3</sub> substrates are thicker (growth rate of  $3.50 \,\mu\text{m min}^{-1}$ ) than on the microsensor ones (Fig. S4) at equal deposition time. This was due to various reasons, like different heat transfer coefficients, absence of the shadowing mask on which significant deposition took place rather than on the microsensor substrate etc. Error bars indicate the variation from 40 different measurements across each substrate.



**Figure S7.** Drift. Baseline stability of a 3.1  $\mu$ m thick WO<sub>3</sub> film at 125 °C in synthetic air with 50% RH.



**Figure S8.** Effect of higher CO concentrations. Sensor responses of the thickness-optimized 3.1  $\mu$ m WO<sub>3</sub> film to 1, 20 and 40 ppm CO at 50% RH (at 23 °C). For comparison, the response to 10 ppb NO<sub>2</sub> is indicated by a dashed line. Please note the axis break on the ordinate.

## **Additional references**

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